

Agenda of the National Type Evaluation Program (NTEP) Committee

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Reference
Key Number

500 Introduction

The NTEP Committee will address the following items at its 2003 Interim Meeting. Table A identifies agenda items by Reference Key Number, title, and page number. The fact that an item may appear on the agenda does not mean it will be presented to the NCWM for a vote. Committee members will review their agenda at the Interim Meeting and may withdraw some items, present some items for information and additional study, issue interpretations, or make specific recommendations for votes at the Annual Meeting. The recommendations presented in this agenda are statements of proposal and not necessarily recommendations of the Committee.

Revisions proposed by Committee members are shown in **bold face print** by ~~crossing out~~ information to be deleted and underlining information to be added. New items proposed for addition to NCWM Publication 14 or other documents are designated as such and shown in **bold face print**.

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Details of All Items (In Order by Reference Key Number)

501-1 International Organization of Legal Metrology (OIML) Certificate Project

Source: Carryover Item 501-1

Background: This item is included on the Committee's agenda to provide an update on NTEP's work to issue OIML R 60, "Metrological Regulation for Load Cells" and R 76, "Non-Automatic Weighing Instruments" Certificates.

OIML Certificate System: At the 2002 Annual Meeting, Dr. Charles Ehrlich, NIST International Legal Metrology Group (ILMG, formerly Technical Standards Activities Program) updated the Committee on pending changes to the OIML certificate system. Dr. Ehrlich reports that there is no additional information on the pending changes.

See the 2002 Final Report of the National Type Evaluation Program (NTEP) Committee for additional background information.

501-2 Test Data Exchange Agreements

Source: Carryover Item 501-2

Background/Discussion: This item is included on the Committee's agenda to provide an update on NTEP's work to establish bilateral agreements.

In April 1998, representatives of the NCWM, NIST International Legal Metrology Group (ILMG, formerly Technical Standards Activities Program), NIST Weights and Measures Division (formerly Office of Weights and Measures), and other OIML countries met to discuss the development of arrangements for mutually accepting type evaluation test data among participating OIML countries. Under such an arrangement, manufacturers would be able to submit their equipment to any of the participating countries for testing to OIML-recommended requirements. The resulting test data would be accepted by other participants, as a basis for issuing each country's own type approval certificate. The following is a report on the three types of test data exchange agreements.

Mutual Acceptance Arrangement (MAA): Dr. Ehrlich, ILMG has indicated that there have been no activities on the MAA since the report to the NTEP Committee during the 2002 NCWM Annual Meeting.

Bilateral Agreements: At the 2001 NCWM Annual Meeting, the NTEP Committee reported that Germany's Physikalisch-Technische Bundesanstalt (PTB) has approached NCWM with a proposal to establish a bilateral agreement between NTEP and PTB in the area of load cells and non-automatic weighing instruments. Additionally, NTEP representatives visited the Nederlands Meetinstituut (NMI) in the Netherlands and the National Weights and Measures Laboratory (NWML) in the United Kingdom several years ago to discuss the possibility of establishing bilateral agreements to mutually recognize type evaluation test data. The NCWM Board of Directors believes that other countries may express a similar interest. The Board remains open to the possibilities of establishing agreements with these and other countries to mutually recognize type evaluation test data. The Board does not wish to establish exclusive agreements and is willing to consider working with any interested country.

During the 2003 NCWM Interim Meeting, Stephen Patoray, NTEP Director, will update the NTEP Committee on the progress of any bilateral agreements.

NTEP-Canada Mutual Recognition Program: At the 2002 NCWM Annual Meeting, NTEP Chairman Louis Straub announced that an agreement was reached between NCWM and Canada to expand the NTEP-Canada Mutual Recognition Program to include retail motor-fuel dispensers. The agreement is a two-year pilot program that recognizes test data collected at the Canadian NTEP Participating Laboratory for use in issuing an NTEP Certificate of Conformance.

Stephen Patoray and Louis Straub will update the Committee on the progress to implement the agreement and a meeting with the NTEP Participating Laboratories and Measurement Canada in October 2002.

See the 2002 Final Report of the NTEP Committee for additional background information.

501-3 Adoption of Uniform Regulation for National Type Evaluation by States

Source: Carryover Item 501-3

Background/Discussion: The Scale Manufacturers Association (SMA) has hosted NTEP adoption and implementation meetings for state directors at each regional weights and measures association conference. These meetings enable jurisdictions to share information about adopting and implementing NTEP in their respective jurisdictions, encourage non-NTEP jurisdictions to adopt the regulation, and allow current NTEP jurisdictions to share ideas on how to make enforcement more effective and uniform among the States. The meetings also provide NTEP management with information related to areas in which the operation and implementation of the program can be improved. Several questions have been posed at these meetings about issues associated with NTEP interpretation or practice. Comments from 1997 to 2001 have been summarized, without attribution, and are available for review and download on the SMA web site at <http://www.scalemanufacturers.org>.

SMA will update the NTEP Committee on two new standards for weighing devices being developed by SMA. The standards are intended to promote uniformity in audit trail information and RFI/EMI test procedures. The first standard addresses the access of audit trail information. At the 2002 Interim Meeting, Daryl Tonini, SMA, noted that this standard would be available early in May 2002 to any manufacturer who might be interested in adopting a standard method of accessing audit trail information. The second standard addresses RFI/EMI Field Test Procedures. About 20 years ago, SMA developed a document outlining RFI/EMI Test Procedures; this document, however, was based on the technology in place at that time. SMA is in the process of updating the procedures to reflect current technology. SMA hopes to raise the level of understanding and interest in both these standards at the 2002 regional weights and measures meetings.

SMA will also update the NTEP Committee on the status of SMA's drive to assist States to adopt the Uniform Regulation for National Type Evaluation and the Uniform Regulation for the Voluntary Registration of Servicepersons and Service Agencies.

See the 2002 Final Report of the NTEP Committee for additional background information.

501-4 NTEP Policy: Challenges to a Certificate of Conformance and Verification that Production Meets Type

Source: Carryover Item 501-4

Background: This item has been moved to the NCWM Board of Directors Interim Agenda. See the 2002 Final Report of the National Type Evaluation Program Committee for additional background information.

501-5 NTEP Participating Laboratories and Evaluations Reports

Source: Carryover Item 501-5

Background: At the 2003 NCWM Interim Meeting, Stephen Patoray, NTEP Director will update the Committee on NTEP laboratory and administrative activities since October 1, 2001. A report of NTEP Laboratory Activities will be distributed at the 2003 NCWM Interim Meeting.

The NTEP Weighing and Measuring Laboratories held a joint meeting in June 2002 in Albany, NY. Mr. Patoray reported that the agenda topics for this meeting focused heavily on technical training issues for the laboratories. The NTEP Weighing Laboratories also met September 29, 2002, before the meeting of the Weighing Sector in Annapolis, MD. The NTEP Measuring Laboratories met prior to the October 2002 annual meeting of the Measuring Sector in Richmond, VA. The next laboratory meeting is planned for April 2003, in Sacramento, CA.

Mr. Patoray reported that a policy to expedite the process for issuing a CC after a device completes a successful evaluation would go into effect by January 1, 2003, for NTEP applicants that desire the expedited CC process. The NTEP process is in response to concerns from manufacturers that the delay between the date an evaluation was completed and the date CC numbers were assigned would hold up production and distribution of devices. In summary, the plan requires an applicant and NTEP to agree upon the testing to be performed and the contents of a draft CC prior to the start of an evaluation. The final CC and number would be ready for signature and distribution at the conclusion of a successful evaluation. The plan was discussed at the 2002 National Type Evaluation Technical Committee (NTETC) Sectors and BOD meetings.

See the 2002 final report of the NTEP Committee for additional background information.

501-6 NTETC Sectors Reports

Source: Carryover Item 501-6

Background: The Committee will hear an update on the activities of the National Type Evaluation Technical Committee (NTETC) Sectors at the 2003 NCWM Interim Meeting. Outlined below is a brief summary of Sector activities since the 2002 NCWM Annual Meeting.

Grain Moisture Meter and NIR Protein Analyzer Sectors: The NTETC Grain Moisture Meter and NIR Protein Analyzer Sectors held a joint meeting in Kansas City, MO on August 21-23, 2002. A summary of these joint meetings was distributed to Sector members in October 2002. The summary will be provided to the Committee prior to the 2003 NCWM Interim Meeting. The next meeting of the Grain Moisture Meter and NIR Protein Analyzer Sectors is scheduled for August 20-22, 2003 in Kansas City, MO. For questions on the current status of Sector work or to propose items for a future meeting, please contact the Sector Technical Advisors, Diane Lee, NIST WMD, or Jack Barber, J.B. Associates. Ms. Lee can be reached by telephone at 301-975-4405, by fax at 301-926-0647, by e-mail at diane.lee@nist.gov, or in writing at NIST, 100 Bureau Drive – Stop 2600, Gaithersburg, MD 20899-2600. Mr. Barber can be reached by telephone at 217-483-4232, by fax at 217-483-3712, by e-mail at jbarber@cityscape.net, or in writing at J.B. Associates, 10349 Old Indian Trail, Glenarm, IL 62536.

Measuring Sector: The NTETC Measuring Sector met October 11-12, 2002, in Lexington, KY. A summary of that meeting will be distributed to the Sector in January 2003. The summary will be provided to the NTEP Committee prior to the 2003 NCWM Interim Meeting. The next meeting of the Measuring Sector is scheduled for October 3-4, 2003, in Charlotte, NC, in conjunction with the Southern Weights and Measures Association's Annual Meeting. For questions on the current status of Sector work or to propose items for a future meeting, please contact the Sector Technical Advisor Richard Suiter, NIST WMD. Mr. Suiter can be reached by telephone at 301-975-4406, by fax at 301-926-0647, by e-mail at rsuiter@nist.gov, or in writing at NIST, 100 Bureau Drive – Stop 2600, Gaithersburg, MD 20899-2600.

Weighing Sector: The NTETC Weighing Sector met September 30 - October 2, 2002 in Annapolis, MD. A draft summary will be distributed to Sector members in early December 2002. The meeting summary will be provided to the Committee prior to the 2003 NCWM Interim Meeting. The next Weighing Sector meeting is tentatively scheduled for September 11-13, 2003, in Fresno, CA, and will be held in conjunction with the Western Weights and Measures Association's Annual Meeting. For questions on the current status of Sector work or to propose items for a future meeting, please contact the Sector Technical Advisor Steven Cook, NIST WMD. Mr. Cook can be reached by telephone at 301-975-4003, by fax at 301-926-0647, by e-mail at stevenc@nist.gov, or in writing at NIST, 100 Bureau Drive – Stop 2600, Gaithersburg, MD 20899-2600.

Automatic Weighing Systems Working Group (AWS): The AWS Working Group met on October 2-3, 2002, in Annapolis, MD, following the meeting of the NTETC Weighing Sector response to remaining issues related to a proposal to change the status of the tentative AWS Code in NIST Handbook 44. The Work Group dealt with several items related to the current NCWM Publication 14 NTEP Draft Checklist and Test Criteria. The AWS Work Group made several suggestions for amending language in Handbook 44 and will be submitting their recommendations to the NCWM S&T Committee and the NTEP Committee prior to the 2003 NCWM Interim Meeting. Contact Stephen Patoray, NTEP Director, or NIST WMD Technical Advisor, Steve Cook, to request a copy of the proposed changes. Mr. Patoray can be reached by email at spatoray@mgmtsol.com. Steve Cook can be reached by telephone at 301-975-4003, by fax at 301-926-0647, by email at steven.cook@nist.gov, or in writing at NIST, 100 Bureau Drive-Stop 2600, Gaithersburg, MD 20899-2600.

NTETC Sector Summaries: At the 2002 Annual Meeting, Mr. Straub discussed the whether or not it is necessary to publish the NTETC Sectors summaries as part of the Interim Agenda and Interim Committee Reports. The summaries currently account for more than one third of the size of the referenced publications. The NCWM Board of Directors and NTEP Committee agreed that the Sector summaries do not need to be published in the NCWM Interim Agendas and Committee Reports for the Annual Meeting. The NTEP Committee will continue to receive copies of the summaries prior to the NCWM Interim Meeting for their review and approval. The NTETC Sector summaries will continue to be included as appendices in the NCWM Annual Reports. Additionally, future Interim Agendas and Committee Reports will state that the NTETC Sector summaries are available upon request from NCWM and NIST.

501-7 Grain Moisture Meter (GMM) and Near Infrared (NIR) Instruments Dual Certification – Can a Single Certificate be Issued?

Source: NTETC GMM and NIR Sector

Background: Of the five Grain Moisture Meter (GMM) types with active NTEP Certificates of Conformance (CC's), two are whole-grain Near Infrared (NIR) Instruments with the potential to seek certification as NIR Grain Analyzers. In a previous Sector meeting, the question was raised as to whether a single CC could be issued to cover devices certified as both GMMs and NIR Grain Analyzers. Time constraints caused consideration of this question to be postponed to a future meeting.

In deciding whether a single CC could be issued to cover devices certified as both GMMs and NIR Grain Analyzers, there are two requirements to consider:

- 1) CC's for GMMs automatically expire July 1. To maintain "active" status, meters must remain in the NTEP ongoing calibration program and the CC's must be reissued annually with valid calibration constants for moisture.
- 2) NIR Grain Analyzers that display a measured whole grain moisture value are required to comply with the requirements of the GMM Code and be type approved as a grain moisture meter.

When an instrument has been approved under both codes, it would seem that NIR Grain Analyzer CC's are subordinate to GMM CC's, because failure to maintain an "active" GMM CC would automatically invalidate the corresponding NIR Grain Analyzer CC. A single CC, such as a "GMM CC with NIR Grain Analyzer Certification" would have to be reissued annually (and whenever a calibration change is made) so there would be no ambiguity regarding the NTEP status of the instrument and its calibrations. Weights and Measures personnel would have only one CC number to check. Manufacturers would have only one CC to maintain per instrument type. Marking requirements would be simplified. The maintenance fee structure for a CC with a "certification" for compliance with another code could be set to recover any loss in NCWM, Inc. revenue that would result from the elimination of the second certificate.

Recommendation: The Sector agreed to ask that the NTEP Committee consider recommending that NCWM, Inc. authorize issuing a single CC for devices successfully type evaluated under two inter-related codes (e.g., a "Grain Moisture Meter CC with Near Infrared Grain Analyzer Certification" or, simply, "NIR Grain Analyzer with Dual Certification").

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National Type Evaluation Program Committee